

APPLICATION DATA SHEET

Electronic Version v14

Stylesheet Version v14.0

Title of Invention

METHOD TO SELECTIVELY CORRECT CRITICAL DIMENSION ERRORS IN THE SEMICONDUCTOR INDUSTRY

Application Type: regular, utility

Attorney Docket Number: BUR920040086US1

Correspondence address:

Customer Number:

30449

30449

Inventors Information:

Inventor 1:

Applicant Authority Type: Inventor
Citizenship: US
Given Name: Jed
Middle Name: H.
Family Name: Rankin
City of Residence: South Burlington
State of Residence: VT
Country of Residence: US
Address-1 of Mailing Address: 211 Juniper Drive
Address-2 of Mailing Address:
City of Mailing Address: South Burlington
State of Mailing Address: VT
Postal Code of Mailing Address: 05403
Country of Mailing Address: US
Phone:
Fax:
E-mail:

Inventor 2:

Applicant Authority Type: Inventor
Citizenship: US
Given Name: Andrew
Middle Name: J.
Family Name: Watts

City of Residence: Essex
State of Residence: VT
Country of Residence: US
Address-1 of Mailing Address: 20 Cedar Street
Address-2 of Mailing Address:
City of Mailing Address: Essex
State of Mailing Address: VT
Postal Code of Mailing Address: 05452
Country of Mailing Address: US
Phone:
Fax:
E-mail:

Attorney Information:

practitioner(s) at Customer Number:

30449 *30449*

as our attorney(s) or agent(s) to prosecute the application identified above, and to transact all business in the United States Patent and Trademark Office connected therewith.

Assignee 1:

Organization Name: International Business Machines Corporation
Address-1 of Mailing Address: New Orchard Road
Address-2 of Mailing Address:
City of Mailing Address: Armonk
State of Mailing Address: NY
Postal Code of Mailing Address: 10504
Country of Mailing Address: US
Phone:
Fax:
E-mail: